

<b>Notice of References Cited</b>		Application/Control No. 10/549,820	Applicant(s)/Patent Under Reexamination HESKE ET AL.	
		Examiner MICHAEL C. STOUT	Art Unit 3736	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,718,237 A	02-1998	Haaga, John R.	600/564
*	B	US-6,033,369 A	03-2000	Goldenberg, Alec	600/567
*	C	US-6,162,203 A	12-2000	Haaga, John R.	604/272
*	D	US-6,221,029 B1	04-2001	Mathis et al.	600/564
*	E	US-6,273,861 B1	08-2001	Bates et al.	600/567
*	F	US-6,290,476 B1	09-2001	Wu, Scott	417/549
*	G	US-6,514,215 B1	02-2003	Ouchi, Teruo	600/564
*	H	US-2003/0088153 A1	05-2003	Carrillo et al.	600/114
*	I	US-2003/0093058 A1	05-2003	Siang Teo, Richard Keng	604/506
*	J	US-2003/0199753 A1	10-2003	Hibner et al.	600/411
*	K	US-7,156,836 B2	01-2007	Teo, Richard Keng Siang	604/508
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.